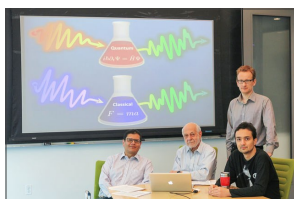
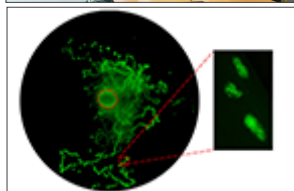


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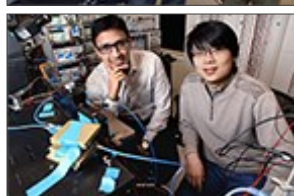
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faculty highlight



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CALL FOR PROPOSALS

proposals

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Deadline: Wednesday, May 31, 2017, 5:00 PM

NIH High-End Instrumentation Grant (HEI) Program encourages applications from groups of NIH-supported investigators to purchase or upgrade a single item of expensive, specialized, commercially available instruments or integrated systems that cost at least \$600,001. The maximum award is \$2,000,000. [READ MORE](#)

Deadline: Wednesday, May 31, 2017, 5:00 PM

FOR ASSISTANCE IN SUBMITTING THIS OR ANY OTHER PROPOSALS, PLEASE CONTACT NANCY YOUNG (8-2553 or nancyy@princeton.edu)

PRISM | PCCM SEMINAR SERIES

March 1

Howard Milchberg
University of Maryland

March 8

Efthimios Kaxiras
Harvard University

April 5

Linda Nazar
University of Waterloo

For a complete schedule, go to MATERIALS.PRINCETON.EDU

NEW EQUIPMENT IN THE IAC

Zeiss Versa 520 3D X-ray Microscope

A new addition in the IAC is the Zeiss Versa 520 3D X-ray microscope, owing to a NSF-MRI award. The 520 Versa is a non-destructive submicron X-ray instrument. Its industry-leading resolution and contrast achieves spatial resolution of 0.7 μm and minimal achievable voxel of 70 nm. This system bridges the resolution gap between light and electron microscopes enabling easy, non-destructive 3D reconstructions of samples. It is equipped with:

- Dual Scan Contrast Visualizer (DSCoVer), enabling compositional probing through overlay of imaging data of a single sample at two different X-ray spectra
- High-Aspect Ratio Tomography (HART) for higher throughput imaging for flat samples like semiconductor packages and boards
- Automated filter changer (AFC) for easy X-ray spectrum tuning
- Wide field mode & vertical stitching for extended imaging of larger samples
- Flat panel extension (FPX) to image significantly larger samples (beyond 5" diameter)
- CT50000-TEC in-situ interface kit for heating, cooling, tension and compression stage

